

PATENT  
Docket No.: M4065.0215/P215

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

RECEIVED

MAY 23 2000  
TOM 700 MAIL ROOM

In re Patent Application of:  
Eugene DeRosa et al.

Serial No.: 09/516,581

Filed: March 1, 2000

Group Art Unit: Not Yet Assigned

Examiner: Not Yet Assigned



For: METHOD FOR MEASURING  
REGISTRATION OF  
OVERLAPPING MATERIAL  
LAYERS OF AN INTEGRATED  
CIRCUIT

Assistant Commissioner for Patents  
Washington, D.C. 20231

**REQUEST FOR APPROVAL OF DRAWING CORRECTION**

Dear Sir:

Applicants hereby request Examiner approval of the drawing corrections shown in red on the attached one (1) sheet, of Fig. 5, submitted herewith for filing in the above-identified Patent Application. The corrections remove unnecessary verbage and numerical information from Fig. 5.

Favorable consideration of the enclosed corrected drawing is respectfully requested.

Dated: April 27, 2000

Respectfully submitted,

By   
\_\_\_\_\_  
Thomas J. D'Amico

Registration No.: 28,371  
DICKSTEIN SHAPIRO MORIN &  
OSHINSKY LLP  
2101 L Street NW  
Washington, DC 20037-1526  
(202) 785-9700

Attorneys for Applicant